

Notice of References Cited

Application/Control No.

09/532,915

Applicant(s)/Patent Under
Reexamination
HAYAKAWA ET AL.

Examiner

A. Sefer

Art Unit

2826

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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-5,73,325 | 06-1998 | Teramoto | 438/151 |
| | B | US-5,508,532 | 04-1996 | Teramoto | 257/59 |
| | C | US-6,093,577 | 07-2000 | Van der Groen | 438/30 |
| | D | US-6,087,229 | 07-2000 | Aronowitz et al | 438/287 |
| | E | US-5,108,843 | 04-1992 | Ohtaka et al | 428/446 |
| | F | US-5,273,920 | 12-1993 | Kwasnick et al | 438/40 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|----------------|----------------|
| | N | JP 9-162405 | 06-1997 | Japan | Yamazaki et al | |
| | O | WO 99/10918 | 03-1999 | PCT | Iyer et al | |
| | P | JP 11-223839 | 08-1999 | Japan | Misawa et al | |
| | Q | JP 10-135469 | 05-1998 | Japan | Yamazaki et al | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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